

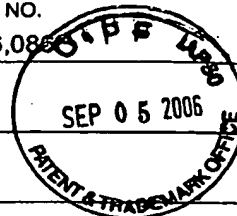
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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250132US2TTCRD DIV		SERIAL NO. 10/796,086 New Div Appln.	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shiho OKUNO, et al.			
				FILING DATE Herewith		GROUP Art Unit 3729	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ADT	AA	6,469,926	10-2002	Chen, Eugene Youjun	-	-	
ADT	AB	2001/0009063	07/2001	Saito et al.	-	-	
ADT	AC	2002/0051380	05/2002	Kamiguchi et al.	-	-	
	AD						
	AE						
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	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
ADT	AO	JP 2000-293982 ✓	10-2000	Japan			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
ADT	AW	N. GARCIA, et al., "Magnetoresistance in Excess of 200% in Ballistic Ni Nanocontacts at Room Temperature and 100 Oe," PHYSICAL REVIEW LETTERS, Vol. 82, No. 14, April 5, 1999, pp. 2923-2926					
ADT	AX	J.J. VERSLUIS, et al., "Magnetoresistance of Half-Metallic Oxide Nanocontacts," PHYSICAL REVIEW LETTERS, Vol. 87, No. 2, July 9, 2001, pp. 026601-1 through 026601-4					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /A. Dexter Tugbang/				Date Considered 9/30/06			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
250132US2RD DIVSERIAL NO.
10/796,085

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Shiho OKUNO, et al.FILING DATE
March 10, 2004GROUP
3729

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
ADT	AO	11-510911	09/21/99	Japan		x
	AP	02-173278	07/04/90	Japan (with English abstract)		x
	AQ	11-293481	10/26/99	Japan (with English abstract)		x
	AR	07-022399	01/24/95	Japan (with English abstract)		x
	AS	05-160123	06/25/93	Japan (with English abstract)		x
ADT	AT	WO 97/47982	12/18/97	WIPO		x
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner /A. Dexter Tugbang/

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